

Search Notes**Application/Control No.**

10/812,105

Examiner

Andrew Lee

**Applicant(s)/Patent under
Reexamination**

JEONG ET AL.

Art Unit

2416

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
See EAST		12/19/2008	al

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor and Interference Search See EAST	12/19/2008	AL